ABSTRACT

A SCATTEROMETER, A LITHOGRAPHIC APPARATUS AND A FOCUS ANALYSIS METHOD

To detect whether a substrate is in the focal plane of a scatterometer the cross-sectional area of said radiation above a predetermined value is detected both in front of and behind the back focal plane of the optical system of the scatterometer. The detection positions in front of and behind the back focal plane should preferably be equidistant from the back focal plane along the path of the reflected radiation so that a simple comparison will determine whether the substrate is in the focal plane of the scatterometer.

[Fig. 6]